

STF11NM50N

N-channel 500 V, 0.40 Ω typ., 8.5 A MDmesh™ II Power MOSFET in a TO-220FP package

Datasheet - production data

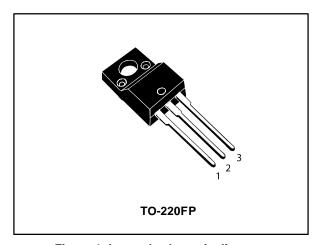
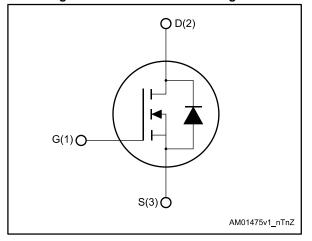


Figure 1: Internal schematic diagram



Features

Order code	V _{DS} @ T _J max	R _{DS(on)} max	ID
STF11NM50N	550 V	0.47 Ω	8.5 A

- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance

Applications

Switching applications

Description

This device is an N-channel Power MOSFET developed using the second generation of MDmesh™ technology. This revolutionary Power MOSFET associates a vertical structure to the company's strip layout to yield one of the world's lowest on-resistance and gate charge. It is therefore suitable for the most demanding high efficiency converters.

Table 1: Device summary

Order code	Marking	Package	Packaging
STF11NM50N	11NM50N	TO-220FP	Tube

Contents STF11NM50N

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STF11NM50N Electrical ratings

1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit	
V _{DS}	Drain-source voltage 500			
V_{GS}	Gate-source voltage	±25	V	
I _D ⁽¹⁾	Drain current (continuous) at T _C = 25 °C	8.5	Α	
I _D ⁽¹⁾	Drain current (continuous) at T _C = 100 °C		Α	
I _{DM} (1)(2)	Drain current (pulsed)	34	Α	
Ртот	Total dissipation at T _C = 25 °C	25	W	
dv/dt (3)	Peak diode recovery voltage slope	15	V/ns	
V _{ISO}	Insulation withstand voltage (RMS) from all three leads to external heat sink (t = 1 s; T_C = 25 °C)	2500	V	
T _{stg}	Storage temperature range	-55 to 150		
Tj	Operating junction temperature range	-55 (0 150	°C	

Notes:

Table 3: Thermal data

Symbol	Parameter	Value	Unit
R _{thj-case}	Thermal resistance junction-case max	5	°C/W
R _{thj-amb}	Thermal resistance junction-ambient max	62.5	°C/W

Table 4: Avalanche characteristics

Symbo	Parameter	Value	Unit
I _{AR}	I _{AR} Avalanche current, repetitive or not-repetitive (pulse width limited by T _{j max})		А
Eas	Single pulse avalanche energy (starting T _J =25 °C, I _D =I _{AR} , V _{DD} =50 V)	150	mJ

⁽¹⁾Limited by maximum junction temperature

 $[\]ensuremath{^{(2)}}\mbox{Pulse}$ width limited by safe operating area.

 $^{^{(3)}}I_{SD} \leq 8.5~A,~di/dt \leq 400~A/\mu s,~V_{DS(peak)} \leq V_{(BR)DSS}, V_{DD} \leq 80\%~V_{(BR)DSS}$

Electrical characteristics STF11NM50N

2 Electrical characteristics

(T_{CASE} = 25 °C unless otherwise specified)

Table 5: On/off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	I _D = 1 mA, V _{GS} = 0 V	500			V
	Zara gata valtaga drain	V _{GS} = 0 V, V _{DS} = 500 V			1	
I _{DSS} Zero gate voltage drain current		$V_{GS} = 0 \text{ V}, V_{DS} = 500 \text{ V},$ $T_{C} = 125 ^{\circ}\text{C}^{(1)}$			100	μΑ
Igss	Gate-body leakage current	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 25 \text{ V}$			±100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	2	3	4	V
R _{DS(on)}	Static drain-source on- resistance	V _{GS} = 10 V, I _D = 4.5 A		0.40	0.47	Ω

Notes:

Table 6: Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
Ciss	Input capacitance		ı	547	-	pF
Coss	Output capacitance	$V_{DS} = 50 \text{ V, f} = 1 \text{ MHz,}$ $V_{GS} = 0 \text{ V}$	1	42	-	pF
Crss	Reverse transfer capacitance	VGS - 0 V	-	2	-	pF
Coss eq.	Equivalent output capacitance	quivalent output capacitance V _{GS} = 0 V, V _{DS} = 0 to 400 V		210	-	pF
Q_g	Total gate charge	$V_{DD} = 400 \text{ V}, I_D = 8.5 \text{ A},$	ı	19	-	nC
Q_{gs}	Gate-source charge	V _{GS} = 10 V (see Figure 14:	ı	3.7	-	nC
Q_{gd}	Gate-drain charge	"Test circuit for gate charge behavior"	1	10	-	nC
R_{G}	Gate input resistance	f=1 MHz, I _D =0 A	-	5.8	-	Ω

Notes:

Table 7: Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)}	Turn-on delay time	$V_{DD} = 250 \text{ V}, I_D = 4.25 \text{ A},$	ı	8	-	ns
t _r	Rise time	$R_G = 4.7 \Omega$, $V_{GS} = 10 V$ (see Figure 13: "Test circuit for	-	10	-	ns
t _{d(off)}	Turn-off delay time	resistive load switching times" and Figure 18: "Switching time waveform")	-	33	-	ns
t _f	Fall time		1	10	-	ns

⁽¹⁾Defined by design, not subject to production test.

 $^{^{(1)}}C_{oss\ eq.}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DS}

Table 8: Source-drain diode

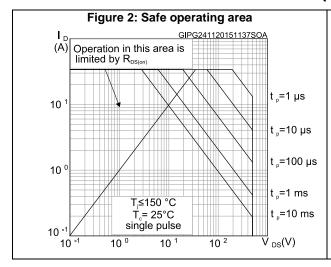
1445.0 01 0041.00 41.4111 41.040						
Symbol	Parameter Test conditions		Min.	Тур.	Max.	Unit
I _{SD} ⁽¹⁾	Source-drain current				8.5	Α
I _{SDM}	Source-drain current (pulsed)		-		34	Α
V _{SD} ⁽²⁾	Forward on voltage	I _{SD} = 8.5 A, V _{GS} = 0 V	ı		1.5	V
t _{rr}	Reverse recovery time	$I_{SD} = 8.5 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}$	ı	230		ns
Qrr	Reverse recovery charge	V _{DD} = 60 V (see <i>Figure 15:</i>	-	2.1		μC
I _{RRM}	Reverse recovery current	"Test circuit for inductive load switching and diode recovery times")	1	18		А
t _{rr}	Reverse recovery time	$I_{SD} = 8.5 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}$	-	275		ns
Qrr	Reverse recovery charge	$V_{DD} = 60 \text{ V}, T_j = 150 \text{ °C}$	ı	2.5		μC
I _{RRM}	Reverse recovery current	(see Figure 15: "Test circuit for inductive load switching and diode recovery times")	-	18		Α

Notes:

⁽¹⁾Pulse width limited by safe operating area.

 $^{^{(2)}}$ Pulsed: pulse duration = 300 μ s, duty cycle 1.5%

2.1 Electrical characteristics (curves)



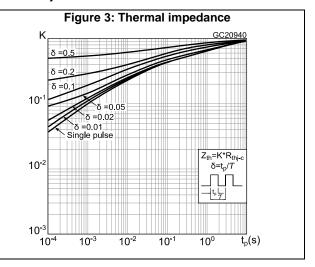
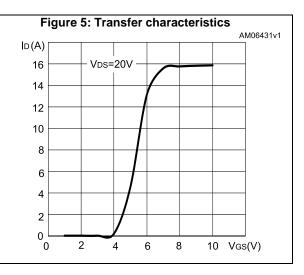
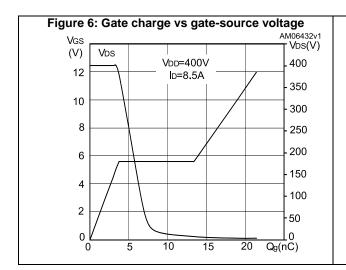
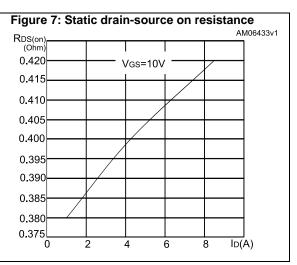
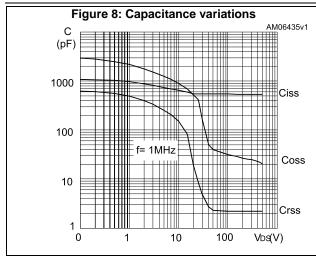


Figure 4: Output characteristics AM06430v1 ID(A) Vgs=10V 16 14 6V 12 10 8 6 5V 4 2 0 10 15 20 25 30 V_{DS}(V) 0









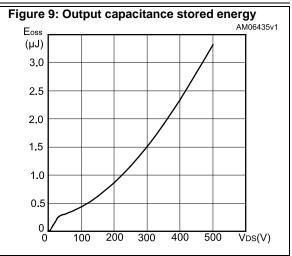
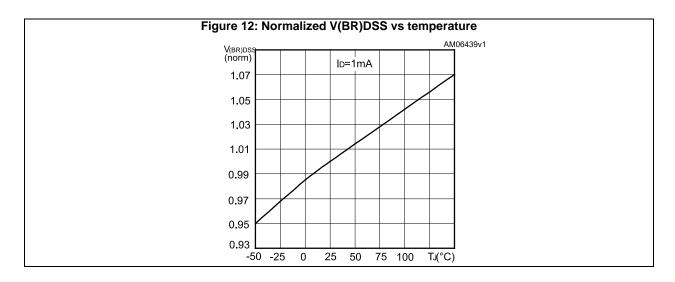


Figure 10: Normalized gate threshold voltage vs temperature AM06436v1 (norm) lo=250µA 1.10 1.00 0.90 0.80 0.70 -50 -25 25 50 75 100 0 T_J(°C)



Test circuits STF11NM50N

3 Test circuits

Figure 13: Test circuit for resistive load switching times

Figure 14: Test circuit for gate charge behavior

12 V 100 η F 100 η

Figure 15: Test circuit for inductive load switching and diode recovery times

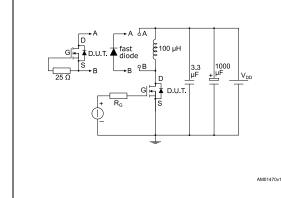


Figure 16: Unclamped inductive load test circuit

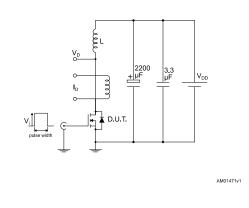


Figure 17: Unclamped inductive waveform

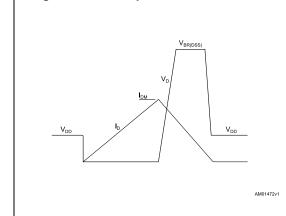
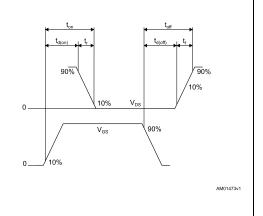


Figure 18: Switching time waveform



STF11NM50N Package information

4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: **www.st.com**. ECOPACK® is an ST trademark.



4.1 TO-220FP package information

Figure 19: TO-220FP package outline

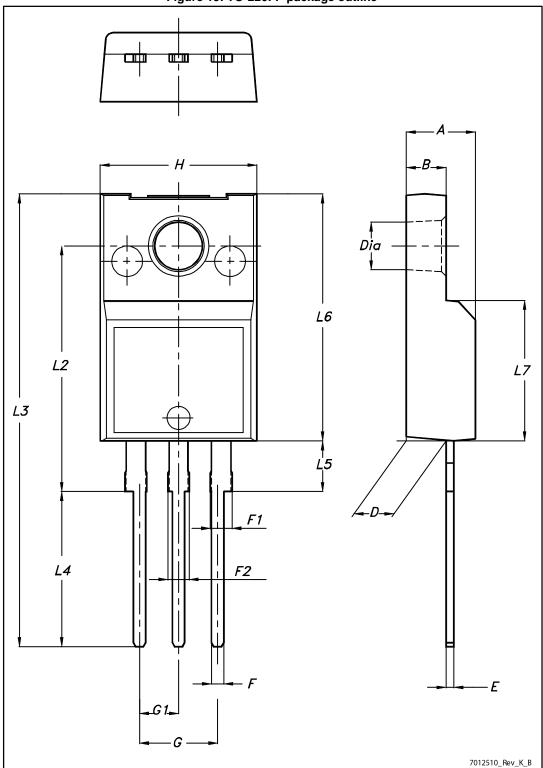


Table 9: TO-220FP package mechanical data

Dim		mm	
Dim.	Min.	Тур.	Max.
Α	4.4		4.6
В	2.5		2.7
D	2.5		2.75
Е	0.45		0.7
F	0.75		1
F1	1.15		1.70
F2	1.15		1.70
G	4.95		5.2
G1	2.4		2.7
Н	10		10.4
L2		16	
L3	28.6		30.6
L4	9.8		10.6
L5	2.9		3.6
L6	15.9		16.4
L7	9		9.3
Dia	3		3.2

Revision history STF11NM50N

5 Revision history

Table 10: Document revision history

Date	Revision	Changes
25-Nov-2015	1	First release. Part number previously included in datasheet DocID17156.
09-Jun-2016	2	Updated I _{GSS} unit from µA to nA in <i>Table 5: "On/off states"</i> . Updated <i>Table 7: "Switching times"</i> modifying references in test conditions. Document reformatted with the current standard with minor text changes to improve readability.

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